

# Interoffice Correspondence

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| <input type="checkbox"/> For Your Comments      | <input type="checkbox"/> Please Route   |
| <input type="checkbox"/> For Your Approval      | <input type="checkbox"/> For Your Information   |
| <input type="checkbox"/> Please Take Action     | <input type="checkbox"/> Note & Return  |
| Due Date _____                                  | <input type="checkbox"/> Note & File  |
| <input type="checkbox"/> Call Me                | <input type="checkbox"/> For Your Signature   |
| <input type="checkbox"/> See Me                 | <input type="checkbox"/> Please Advise Status   |
| <input type="checkbox"/> Per Our Conversation   | <input type="checkbox"/> Per Your Request   |
| <input type="checkbox"/> Read, Initial & Return | <input type="checkbox"/> Please Advise<br>Appropriate Employees<br>In Your Department |

To: Bill Ellis                      Gary Reilly                      Date:                      January 15, 1983  
Bill To                              Kyu Lee  
George James

CC:

From: Vic Belmondo

Subject: Trip Report, Visit to Silicon Valley December 14 through December 17

The attached notes are from my trip to JEDEC meetings and various semi houses in Silicon Valley. The trip was very valuable. Data I/O was received well by all customers. I will be requesting various people to follow up on specific action items.

VEB:lc

*VEB*

Tuesday, December 14, 1982

JEDEC Bipolar:

No unexpected results. No work was done on JEDEC registration on bipolar logic devices.

I presented 3 suggested editorial changes to our format. Two of the three

1. A clarification of link numbering, and
2. Specification of legal ASCII characters

were OK'd. The third,

3. Keying off manufacturer part number

was not accepted for programming algorithm I.D.

Action:

1. Make changes to format, get copy to Jack Kinn
2. Work with Nap and Warren on alternate ideas for I.D. of programming algorithm.

L.S.I. Technology: (P.M.)

Keith Lobo, Mike, Kyu and I discussed computers, programs and software tools used in VLSI (6000 gate gate array design and production).

We discussed size of computers and languages.

In a discussion of testing of LSI gate array devices, Keith said that they only do the amount of testing requested by the customer - no more - or costs would increase. Testing is limited, therefore, in comparison to micro-processors because volume is lower. He suggests there may be a niche market for us, but can't guarantee.

He gave us a lead on a Ph.D. who worked with Dismeyer at Madison who is now at Bell Labs. Kyu will follow up.

Wednesday, December 15, 1982

M.M.I.

Cyrus Tsu

Discussed current status - all OK. Started redesign of Fast PAL die. Wants to figure out one good fix and implement it.

Wants to qualify only 2 programmer manufacturers, and a maximum of 3.

M.M.I. (continued)

Concerned about telling the field about fix. Told him we can work in parallel, factory and field, after we get approval. Probably can tell field first week in January.

Says to expect to always reduce heating.

ECN control of approvals at M.M.I.: engineer to talk, but commitments will be through Charlie Bannon and Cyrus.

Expect parts with more pins than we have.

Wants confidence adapter for control - in field.

Corporate goal is 99% yield. Redundancy will be used to achieve this.

Textool sockets.

Wants people to calibrate their programmers; will add this to data sheets if we ask.

Ralph Burlock - Intersil 6716

P120 sold without 67C16. Need to add software to 120. Promised a temporary fix before Christmas, algorithm by January 15.

Cliff Biggers, A.M.D.

See new Data Book for new specifications.

Talked about PLDS vs. UniPak implementation of X4 registered parts. Need action and decision.

Cliff will have parts in March, customers in April - this is important.

We need to contact Bill Sievers to decide on procedures regarding who standardizes fuse maps for programmable Logic devices.

Bob Osan, Assisted Technology (Kyu, Mike Mraz, Mike Holley, Vic, Charlie)

Expressed proprietary nature of software and what it runs on, after several questions by Kyu. Made arrangements with Charlie to get equipment to him for checkout. Need to follow up this week to see if it happened.

SEEQ, Dan Leonard, Bill Smith

Implement Silicon signatures using one family for SEEQ. Approvals are OK. Dan wants to see a P120 in mid-February for approval.

Needs some clarification all machines, etc. Send him the bulletin we send to customers for P19 update, UniPak II, Gang II and PLDS.

### SEEQ (continued)

See if we can get the Intel 2816 and the SEEQ 2816 at the same erase voltage. One is 9-15V, the other is 14-21V - - this allows the same code for both parts.

Die trace could be added via a select code. I suggested we supply select code to access it, then SEEQ can supply the hex decode to their customers. I forgot what pin is required to go to VHH to read these; it is a completely separate array. See Dan Leonard sheet.

Bill Smith (formerly of Signetics) said that Nap Cavlan probably will make the decisions behind Bob Barker at Signetics.

### Source III - Bob Hartman, Art Aronson

Thinking of large pinout programmable gate array devices. They are still in concept stage. They design 1000 gate gate arrays now. We suggested they bring address out like a PROM, making easier access to fuses. This would avoid programmer development charges.

They are a 4-person company.

Thursday, December 16, 1982

### JEDEC MOS

Various ballots on nonvolatile RAMs and EEPROMs were passed. See attached sheets.

The Byte Wide task group was split up between strategic and tactical.

Don Knowlton from Intel will take strategic portion to define pinouts for word wide PROMs, etc.

Bill Owens of Xicor will probably replace Larry Jordan as chairman of Strategic Task Group. This covers electronic signature and other byte wide pinouts, etc., and X9 parts.

Little of interest was discussed. However, Bill Johnston of Fujitsu said that Fujitsu had approved the Intel algorithm for their parts.

Friday, December 17, 1982

### Signetics - Bob Barker, Bruno, Dave Yeaton, George, George, George James

The meeting split into 2 groups - hardware and software.

Hardware issues:

#### 1. PROMs

82S135 = 1/2 of 82S147. Taken care of, just add to charts, assign codes. Charlie will get us samples.



2. 82S159, etc.

They gave us new fuse address map. We owe them new software to implement.

3. In first quarter of '83 they will present us with all information on 24-pin skinny devices. We told them if it requires hardware development we have 6-9 month lead time.

The design diskette could save Bruno a lot of time. He is willing to be a B site. We send diskette and letter with limitations.

They think SD is hurting them. They want us to build a low-cost programmer. I said we can't, but were interested in educational board/package.

They have some parts that pass fuse verify but don't work in customer circuit. They said they fail fingerprint as well. We will evaluate samples if they send them and help out the customer. More advertising for us.

#### New AIM Algorithm

We discussed algorithm, they need 1 usec and 2 usec - 5 usec pulses on a #6 line. See attached specs. Gary Reilly will study problem and see if there is any way to implement on UniPak.

They still want us to keep total programming energy low. They made a comparison between Data I/O and other manufacturers. See attached sheet.

#### Intel - Bill Carney, Bob Davis, Don Knowlton:

Silicon Signature - Double-check method is OK. (Key in Family Pinout code and programmer checks if OK.)

256K bit parts out in March, need 256K bit RAM.

Still interested in joint promotions of intelligent programming.

Three items discussed were: intelligent identifier  
87128 authenticated PROM  
87100 operating system PROM

We spent three hours discussing these devices. They will visit in January. We will respond then with questions and schedules.

The other issue discussed was bipolar approval on UniPak. Don Knowlton promised to kick it up a level to get cooking on approval again. We should follow up early in January.

VEB:lc  
Attachments

PIN ASSIGNMENTS - SILICON SIGNATURE™

SEEQ TECHNOLOGY, INC.

*	*	*	*	*	-	1		38	-	V <sub>CC</sub>	V <sub>CC</sub>	V <sub>CC</sub>	V <sub>CC</sub>	V <sub>CC</sub>
x	x	x	x	x	-	2		37	-	V <sub>EM</sub>	V <sub>EM</sub>	V <sub>EM</sub>	V <sub>EM</sub>	V <sub>EM</sub>
x	x	x	x	x	x	3		70	V <sub>CC</sub>	x	x	x	x	x
x	x	x	x	x	x	4		75	x	x	x	x	x	x
x	x	x	x	x	x	5		24	V <sub>M</sub>	V <sub>M</sub>	V <sub>M</sub>	V <sub>M</sub>	V <sub>M</sub>	V <sub>M</sub>
x	V <sub>SL</sub>	x	x	x	x	6		23	V <sub>SM</sub>	x	x	x	x	x
SA <sub>3</sub>	SA <sub>3</sub>	SA <sub>3</sub>	SA <sub>3</sub>	SA <sub>3</sub>	SA <sub>3</sub>	7		22	V <sub>SL</sub>	V <sub>SL</sub>	V <sub>SL</sub>	V <sub>SL</sub>	V <sub>SL</sub>	V <sub>SL</sub>
SA <sub>2</sub>	SA <sub>2</sub>	SA <sub>2</sub>	SA <sub>2</sub>	SA <sub>2</sub>	SA <sub>2</sub>	8		21	x	x	V <sub>SL</sub>	V <sub>SL</sub>	x	x
SA <sub>1</sub>	SA <sub>1</sub>	SA <sub>1</sub>	SA <sub>1</sub>	SA <sub>1</sub>	SA <sub>1</sub>	9		20	V <sub>SL</sub>	V <sub>SL</sub>	V <sub>SL</sub>	V <sub>SL</sub>	V <sub>SL</sub>	V <sub>SL</sub>
SA <sub>0</sub>	SA <sub>0</sub>	SA <sub>0</sub>	SA <sub>0</sub>	SA <sub>0</sub>	SA <sub>0</sub>	10		19	O <sub>8</sub>	O <sub>8</sub>	O <sub>8</sub>	O <sub>8</sub>	O <sub>8</sub>	O <sub>8</sub>
O <sub>1</sub>	O <sub>1</sub>	O <sub>1</sub>	O <sub>1</sub>	O <sub>1</sub>	O <sub>1</sub>	11		18	O <sub>7</sub>	O <sub>7</sub>	O <sub>7</sub>	O <sub>7</sub>	O <sub>7</sub>	O <sub>7</sub>
O <sub>2</sub>	O <sub>2</sub>	O <sub>2</sub>	O <sub>2</sub>	O <sub>2</sub>	O <sub>2</sub>	12		17	O <sub>6</sub>	O <sub>6</sub>	O <sub>6</sub>	O <sub>6</sub>	O <sub>6</sub>	O <sub>6</sub>
O <sub>3</sub>	O <sub>3</sub>	O <sub>3</sub>	O <sub>3</sub>	O <sub>3</sub>	O <sub>3</sub>	13		16	O <sub>5</sub>	O <sub>5</sub>	O <sub>5</sub>	O <sub>5</sub>	O <sub>5</sub>	O <sub>5</sub>
GND	GND	GND	GND	GND	GND	14		15	O <sub>4</sub>	O <sub>4</sub>	O <sub>4</sub>	O <sub>4</sub>	O <sub>4</sub>	O <sub>4</sub>

\* - Function Pin, defined for device.

SA<sub>0-3</sub> : Signature Address Lines



Parameter Definition	STAG	Data I/O Rev1 PIPS	Data I/O Logic Pack
Address VIH VIL Tpp td9	4.5V 0V 350µs 200µs	4.5V 0V 1ms NA	4.5V 0 1.4ms NA
VCC VCCP TVCCP Ed1 tr1 tf1	8.4V 120µs 25µs 1.2µs 21µs	8.4V 200µs 140µs 14µs 50µs	8.4V 240µs 50µs 10µs 480µs*
Program/Verify td2 VIH VIL	24µs 4.5V 0V	30µs 4.5V 0V	10µs 4.4V 0V
Using Supply td3 tra td5 tf2 td6	26µs 20µs 14µs 21µs 40µs	25µs 12µs 16µs 21µs NA	40µs 20µs 30µs 35µs NA
Probe td4 Pwp td7	2µs 16µs NA	30µs 24µs NA	36µs 14µs NA
unloaded data I/O	See picture		(32µs LOADED)

S.B.  
Dec 17 1982

# Proposed 82A5195 (A.I.M.) Fusing Algorithm

1. Select Address to be programmed.
2. Verify the output is in the "one state".
3. Raise  $V_{CC}$  to 8.75V.
4. Raise output to 17V no faster than  $1V/\mu\text{sec}$ .
5. Enable CE for  $1\mu\text{sec}$ .
6. Lower the output voltage, then  $V_{CC}$ .
7. Sense the output for a "0".
8. If the output is a "1" repeat fusing procedure steps 3 to 7 with increasing CE pulse width ( $1\mu\text{sec}$  per step) until the output is in the "0 state" -  $5\mu\text{sec max}$ .
9. When pattern is complete, readdress each programmed Address and reprogram with a single  $2\mu\text{sec CE pulse}$ .

diode acts as a clamp

10. components

max = 140

Min = 120



10/10/05

# Proposed 82H\$195 (A.I.M.) Fusing Algorithm

SC

Course  
George 746 1348  
407

